

Search Notes

Application/Control No.

10/710,747

Examiner

Marlon A. Arce-Diaz

Applicant(s)/Patent under
Reexamination

OI, TAKESHI

Art Unit

3611

SEARCHED

Class	Subclass	Date	Examiner
280	281.1 288.2 288.3	9/26/2005	MAA

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
US-PGPUB, JPO, EPO, USPAT	9/26/2005	MAA